



Contribution ID: 261

Type: Oral Presentations

Kinoforms for High Energy Photons

Tuesday, 29 January 2019 15:15 (15 minutes)

Studying materials with high energy (> 50 keV) X-ray photons brings some advantages for materials characterization. For example, the pair distribution function method (PDF) gets better real space resolution with higher energy photons. The ability to focus X-ray beams of high energy photons brings further experimental benefits for materials characterization, including greater flux on small samples, improved signal to background, and also enabling spatial scanning of samples. In this talk, we present our recent results using silicon kinoform lenses to focus X-ray photons with energies as low as 52 keV and as high as 107 keV, measured on beamlines 1-ID and 11-ID-C at the Advanced Photon Source. In a number of experiments, we have created micron and sub-micron beams, in some cases as small as 225 nm. Latest improvements in lens fabrication will also be presented. We will also show a numerical comparison between refractive lenses made from Beryllium, Silicon and Aluminum and kinoform lenses made from Silicon and discuss the relative merits for these high photon energies.

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